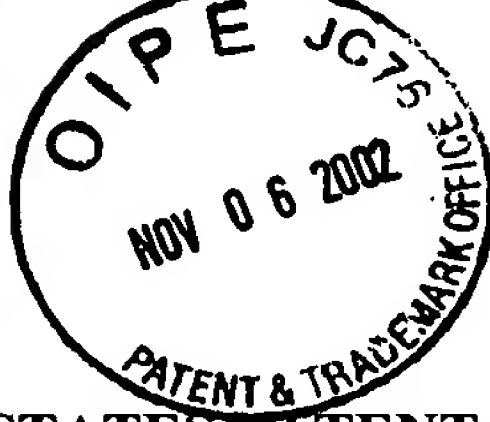


Docket No. 192520US2



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF: Hayashi OTSUKI, et al.

SERIAL NO: 09/594,479

GAU: 2877

FILED: June 14, 2000

EXAMINER: PUNNOOSE, R.

FOR: PARTICLE-MEASURING SYSTEM AND PARTICLE-MEASURING METHOD

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

ASSISTANT COMMISSIONER FOR PATENTS  
WASHINGTON, D.C. 20231

SIR:

Applicant(s) wish to disclose the following information.

REFERENCES

- ☒ The applicant(s) wish to make of record the references listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.
- ☒ A check is attached in the amount required under 37 CFR §1.17(p).

MATCH & RETURN

Handwritten: 15/05/00 #105

RELATED CASES

- ☐ Attached is a list of applicant's pending application(s) or issued patent(s) which may be related to the present application. A copy of the patent(s), together with a copy of the claims and drawings of the pending application(s) is attached along with PTO 1449.
- ☐ A check is attached in the amount required under 37 CFR §1.17(p).

CERTIFICATION

- ☒ Each item of information contained in this information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- ☐ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

DEPOSIT ACCOUNT

- ☒ Please charge any additional fees for the papers being filed herewith and for which no check is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

OBLON, SPIVAK, McCLELLAND,  
MAIER & NEUSTADT, P.C.



22850

Gregory J. Maier

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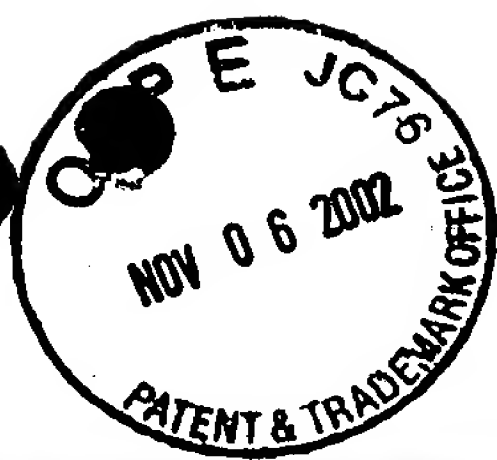
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Dept.: E/M

By: GJM/RTP/KDP/dmr

OSMM&N File No. 192520US2

Serial No. 09/594,479

In the matter of the Application of: Hayashi OTSUKI, et al.

For: PARTICLE-MEASURING SYSTEM AND PARTICLE-MEASURING METHOD

Due Date: October 30, 2002

The following has been received in the U.S. Patent Office on the date stamped hereon:

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